



Provisional program

6th Workshop "Materials Characterisation by the Combined Analysis"

October 19-23, 2015, Trento (Italy)



Monday	Tuesday	Wednesday	Thursday	Friday
<i>Rietveld analysis</i>	<i>Microstructure and nanostructured materials</i>	<i>Diffraction, Reflectivity and Fluorescence combined</i>	<i>Texture and deformations</i>	<i>Rietveld-PDF analysis by electron diffraction and EDS</i>
	9h Microstructure analysis I: theory (Matteo Leoni)	9h Fluorescence: XRF and GIXRF analyses (Christina Strelj)	9h Texture analysis: from pole figures to ODF (Daniel Chateigner)	9h Transmission Electron Microscopy: combining electron diffraction and EDS (Stefano Gialanella)
~10h30 / 11h : coffe break				
10:00h Welcome Introduction: Beam-Matter interaction (Giancarlo Pepponi) Instrumentation and measurements (Henry Pillière)	Microstructure analysis II: Rietveld-PDF analyses (Luca Lutterotti)	Combining Diffraction, Reflectivity and Fluorescence analysis in thin films (Giancarlo Pepponi)	Texture and anisotropy: in situ analysis at high temperature and pressure (Hans-Rudolf Wenk)	Rietveld-PDF analysis on nanomaterials by SAED (Philippe Boullay)
~12h30 / 14h : Lunch				
Classical Rietveld Analysis (Luca Lutterotti)	Practical session: line broadening (size-strain and planar defects) Hands on Maud	Practical session: XRD and XRF combined analysis on bulk materials Hands on Maud	Practical session: Rietveld texture analysis Hands on Maud	Practical session: Ring pattern analysis from electron diffraction images Hands on Maud
~15h30 / 16h : coffe break				
Practical session: Rietveld analysis and Phase Quantification Hands on Maud	Practical session: nanomaterials and Rietveld-PDF analysis Hands on Maud XRD-XRR-XRF laboratory (17:00 – DII/FBK labs)	Practical session: XRR and GIXRF combined analysis on thin films Hands on Maud	Practical session: Rietveld texture-stress analysis on the DAC Hands on Maud	Practical session: combining SAED and EDS Hands on Maud
~18h End of the day				
Welcome Dinner			Social Dinner	